

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/829,275 SUZUKI ET AL.	
		Examiner	Art Unit	Page 1 of 1 MARK R. WENDELL 3635

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0009977	01-2003	Houghton, David L.	52/656.9
*	B	US-5,533,307	07-1996	Tsai et al.	52/167.3
*	C	US-2006/0112652	06-2006	Ichikawa et al.	052/167.1
*	D	US-7,225,588	06-2007	Nakamura et al.	52/167.3
*	E	US-6,826,874	12-2004	Takeuchi et al.	52/167.3
*	F	US-4,409,765	10-1983	Pall, Avtar S.	52/167.1
*	G	US-2005/0005539	01-2005	Nakamura et al.	052/167.3
*	H	US-2007/0240368	10-2007	Tsai et al.	052/167.3
*	I	US-2005/0166487	08-2005	Tsai, Chong-Shien	052/167.3
*	J	US-2004/0107654	06-2004	Powell et al.	052/167.3
*	K	US-6,837,010	01-2005	Powell et al.	52/167.3
*	L	US-2004/0074161	04-2004	Kasai et al.	052/167.1
*	M	US-2005/0036829	02-2005	Trull, Scott E.	403/170

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.